

Notice of References Cited	Application/Control No. 10/713,047	Applicant(s)/Patent Under Reexamination YUEH, WEN HSIANG	
	Examiner Duc M. Nguyen	Art Unit 2618	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,230,029	05-2001	Hahn et al.	455/575.2
*	B	US-2004/0203351 A1	10-2004	Shearer et al.	455/041.1
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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